

Form PTO-1449 U.S. Department of Commerce
(REV. 2-82) Patent and Trademark OfficeAtty. Docket No.
36179/US/2-475387-30Serial No.
10/577,562**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**
(Use several sheets if necessary)Applicant(s)
Seok-Hyun Yun et al.Filing Date
April 27, 2006Confirmation No.
3634**U.S. PATENT DOCUMENTS**

*Exam. Init.	Document No.							Date	Name	Class	Subclass	Filing Date if Appropriate
	4	5	3	3	2	4	7	August 6, 1985	Epworth eeeeee			
	6	7	4	1	3	5	5	May 25, 2004	Drabarek eeeeee			
2005	0	0	7	5	5	4	7	April 7, 2005	Wang eeeeee			
2005	0	0	8	3	5	3	4	April 21, 2005	Riza et al. eeeeee			
	3	9	7	3	2	1	9	August 3, 1976	Tang et al.			
	3	9	8	3	5	0	7	September 28, 1976	Tang et al.			
2006	0	1	0	3	8	5	0	May 18, 2006	Alphonse et al. eeeeee			
	4	8	9	2	4	0	6	January 9, 1990	Waters eeeeee			
	5	7	1	6	3	2	4	February 10, 1998	Toida φ			
	6	4	5	9	4	8	7	October 1, 2002	Chen et al.φ			
2002	0	0	9	3	6	6	2	July 18, 2002	Chen et al. φ			
	6	3	5	9	6	9	2	March 19, 2002	Groot φφφ			
	6	9	0	3	8	2	0	June 7, 2005	Wang φφφφ			
2006	0	2	4	4	9	7	3	November 2, 2006	Yun et al. φφφφφ			
	5	2	2	8	0	0	1	July 13, 1993	Birge et al. φφφφφφ			
	6	6	8	7	0	3	6	February 3, 2004	Riza φφφφφφ			
	4	4	2	8	6	4	3	January 31, 1984	Kay φφφφφφ			
	4	9	6	5	5	9	9	October 23, 1990	Roddy et al. φφφφφφ			

Examiner

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ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /MAL/

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		4	3	0	3	3	0	0	December 1, 1981	Pressiat et al.			
		6	8	3	9	4	9	6	January 4, 2005	Mills et al.			
2004	0	1	3	3	1	9	1		July 8, 2004	Momiuchi et al. φφφφφφφφ			
		5	8	4	0	0	7	5	November 24, 1998	Mueller et al. φφφφφφφφ			
2003	0	2	1	6	7	1	9		November 20, 2003	Debenedictis et al. φφφφφφφφ			
2006	0	1	5	5	1	9	3		July 13, 2006	Leonardi et al. φφφφφφφφ			
2003	0	1	9	9	7	6	9		October 23, 2003	Podoleanu et al. φφφφφφφφφφ			
2004	0	2	1	2	8	0	8		October 28, 2004	Okawa et al. φφφφφφφφφφ			

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Document No.									Date	Country	Class	SubClass	Translator Yes No	
	9	6	2	8	2	1	2		September 19, 1996	WIPO φφφφφφφφφφφ				
	0	9	3	3	0	9	6		August 4, 1999	European φφφφφφφφφφφ				
	4	1	0	5	2	2	1		September 12, 1991	Germany				
	0	1	0	8	5	7	9		February 8, 2001	WIPO φφφφφφφφ				
	9	9	0	5	4	8	7		February 4, 1999	WIPO φφφφφφφφ				
200	5	0	8	2	2	2	5		September 9, 2005	WIPO φφφφφφφφφφφ				
200	4	0	3	4	8	6	9		April 29, 2004	WIPO φφφφφφφφφφφ				

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	0	3	0	5	2	4	7	8	June 26, 2003	WIPO φφφφφφφφφφ				
	200	7	0	3	8	7	8	7	April 5, 2007	WIPO φφφφφφφφφφ				

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 Reference cited in Office Action dated January 10, 2008 for U.S. Patent Application No. 11/435,228
 Reference cited in Office Action dated January 10, 2008 for U.S. Patent Application No. 11/410,937
 Reference cited in Office Action dated January 11, 2008 for U.S. Patent Application No. 11/445,990
 Reference cited in Office Action dated February 4, 2008 for U.S. Patent Application No. 10/861,179
 References cited in International Search Report PCT/US2007/061481 dated March 17, 2008
 References cited in International Search Report PCT/US2007/078254 dated March 28, 2008
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		Copy of PCT International Search Report and Written Opinion for Application No. PCT/US2007/061481 dated March 17, 2008
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		Copy of Statement under Article 19 and Reply to PCT Written Opinion for PCT International Application No. PCT/US2005/043951 dated June 6, 2006
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Examiner /Michael A. Lyons/

Date Considered 08/01/2008

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